

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 295880US2PCT		SERIAL NO. 10/591,433	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Mikio IZUMI, et al.			
				FILING DATE September 1, 2006		GROUP 2108	
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
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	AL						
	AM						
	AN						
<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
/DC/	AO	WO 00/41101	07/13/2000	WIPO			
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
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<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
/DC/	AW	Charles E. STROUD, et al., "Applying Built-In Self-Test to Majority Voting Fault Tolerant Circuits", VLSI Test Symposium, 1998. Proceedings. 16 <sup>th</sup> IEEE Monterey, CA, USA, April 26-30, 1998, Los Alamitos, CA, USA, IEEE COMPUT. SOC, US, April 26, 1998, pages 303-308, XP010277179					
/DC/	AX	R. E. BATTLE, et al., "Reactor Protection System Design Using Application-specific Integrated Circuits", 19000101, January 1, 1900, pages 389-396, XP009106740					
/DC/	AY	T. KOBAYASHI, et al., Database Inspec, The Institution of Electrical Engineers, Stevenage, GB; 1991, "Review of structure and reliability of active delay line", AN 4028563, XP002498963, 1 page (abstract)					
/DC/	AZ	Takashi NANYA, et al., "On signal Transition Causality for Self-Timed Implementation of Boolean Functions", System Sciences, 1993, Proceeding of the Twenty-Sixth Hawaii International Onal Conference on Wailea, HI, USA, January 5-8, 1993, Los Alamitos, CA, USA, IEEE, US, vol. I, January 1993, pages 359-368, XP010640404					
/DC/	BA	B. S. KONG, et al., "CMOS differential logic family with self-timing and charge-recycling for high-speed and low-power VLSI", IEE Proceedings: Circuits Devices and System, Institution of Electrical Engineers, Stenvenage, GB, vol. 150, no. 1, February 6, 2003, pages 45-50, XP006019670				<input type="checkbox"/> Additional References sheet(s) attached	
Examiner /Dwin Craig/ (07/15/2009)					Date Considered		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /DC/ (07/15/2009)